

Fig. 1

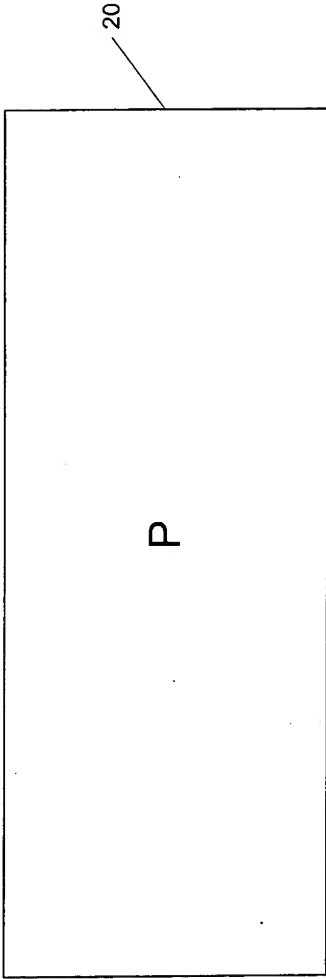
[illegible]

Fig. 2a

FIG. 2b

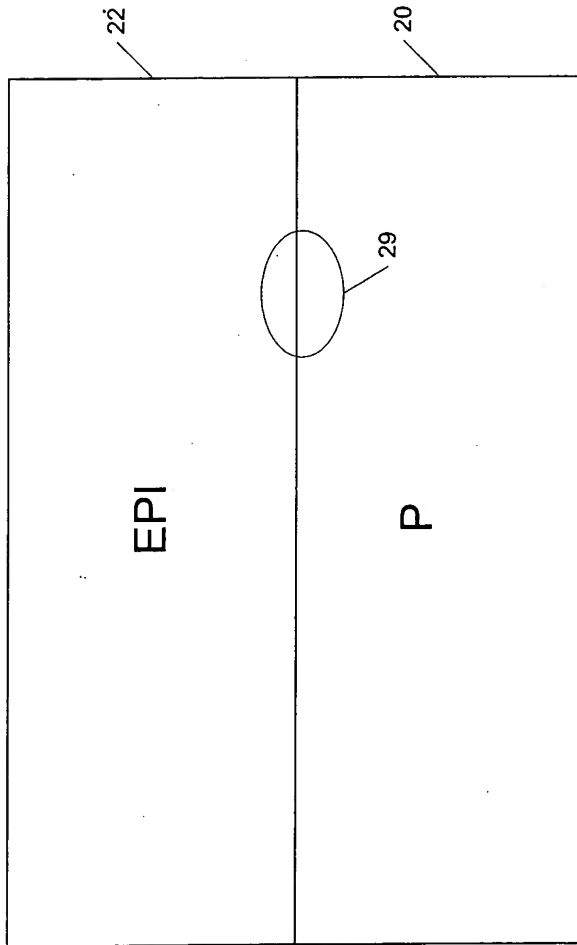


Fig. 2b

Diagram illustrating a cross-sectional view of a semiconductor device. The structure is divided into two main regions: an EPI (Epitaxial) layer on the left and a P layer on the right, separated by a vertical line labeled 20. The EPI layer contains several small rectangular features labeled 24. A circular feature labeled 29 is located in the P layer.

Fig. 2c

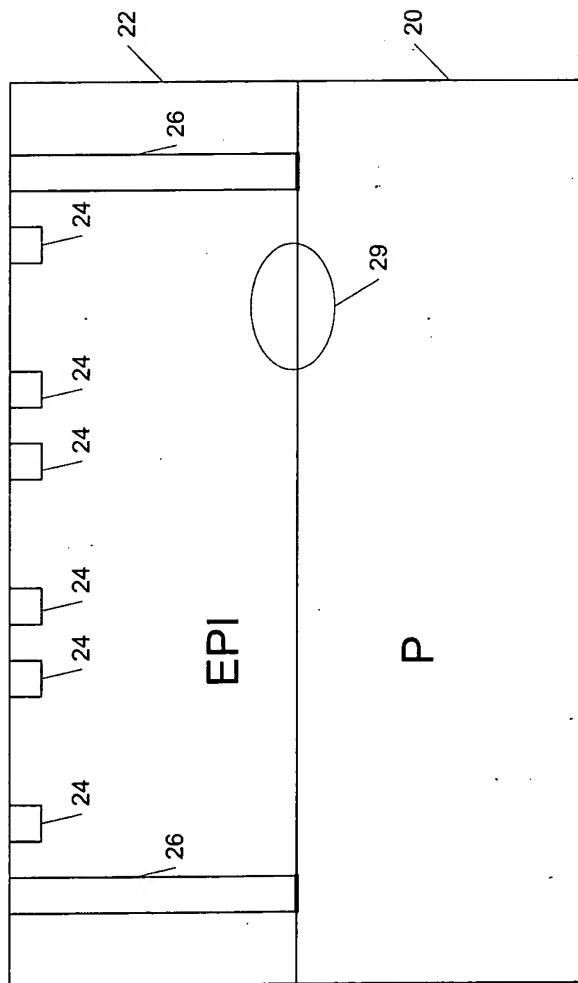


Fig. 2d

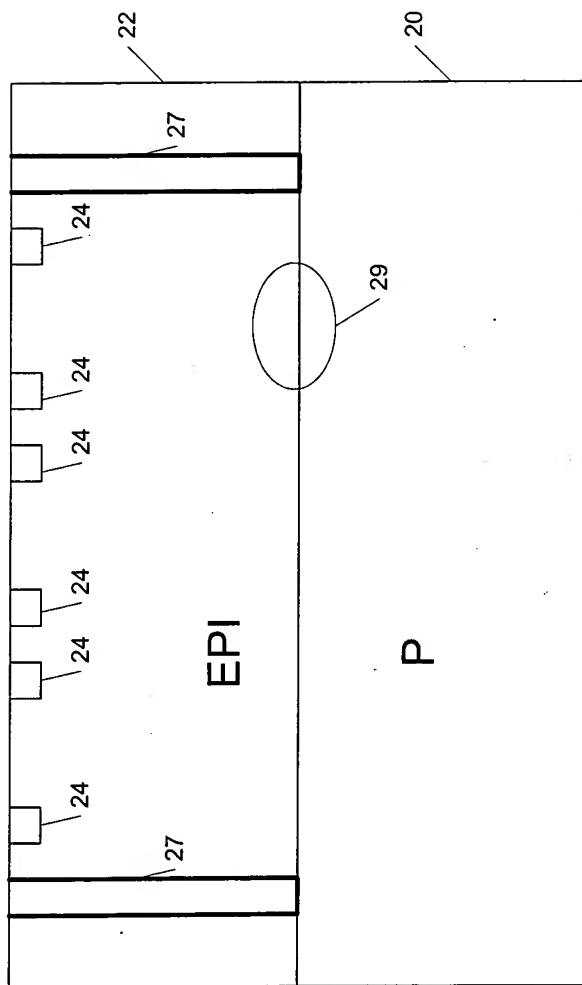


Fig. 2e

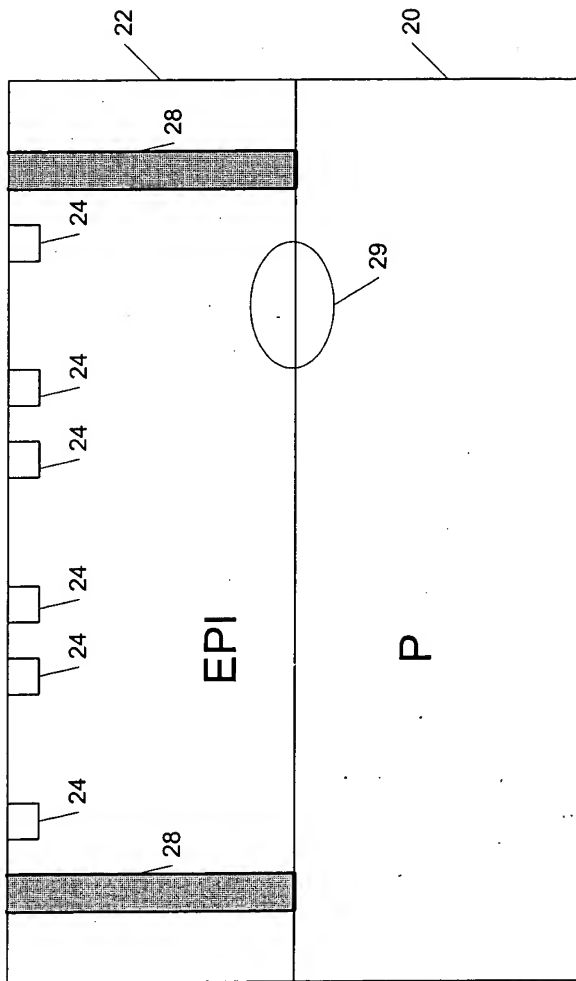


Fig. 2f

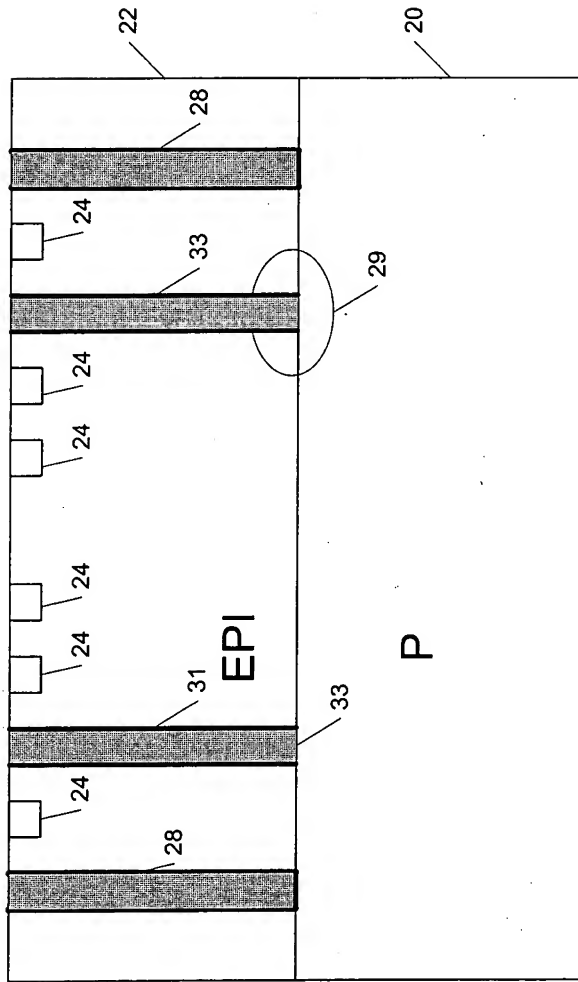


Fig. 2g

14-00000-1-1000-1

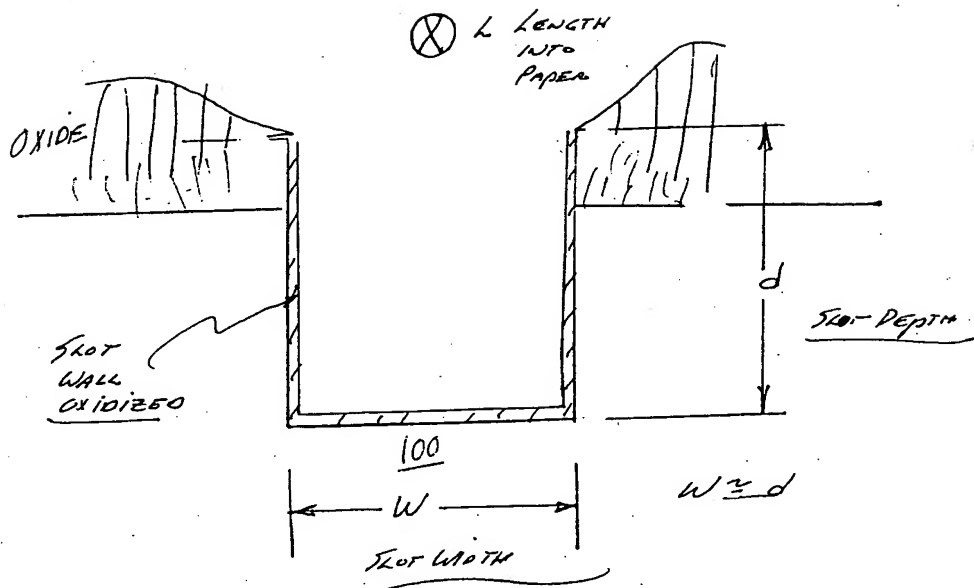


Fig. 3

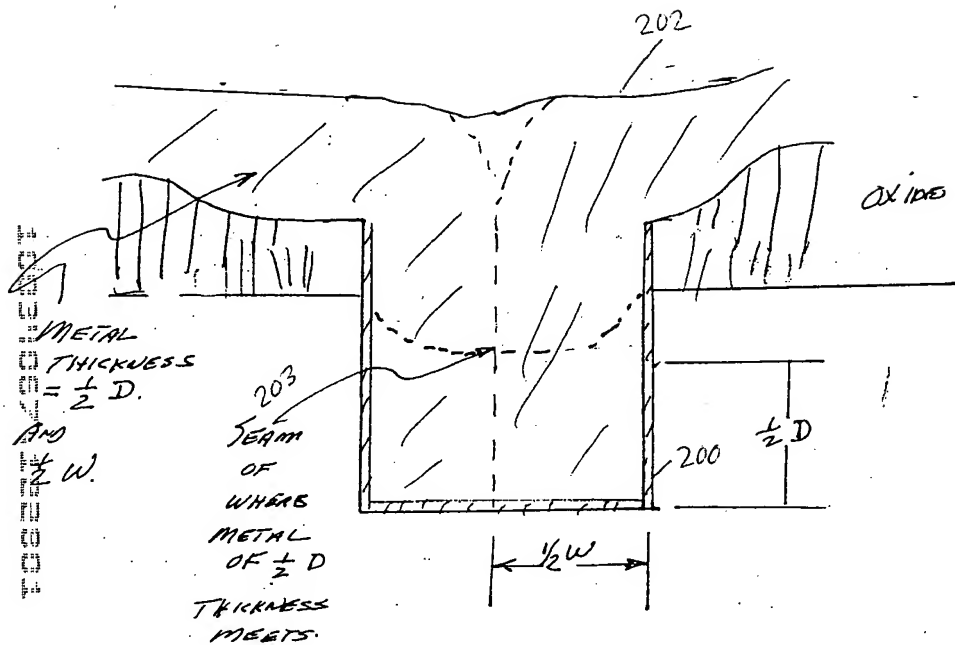
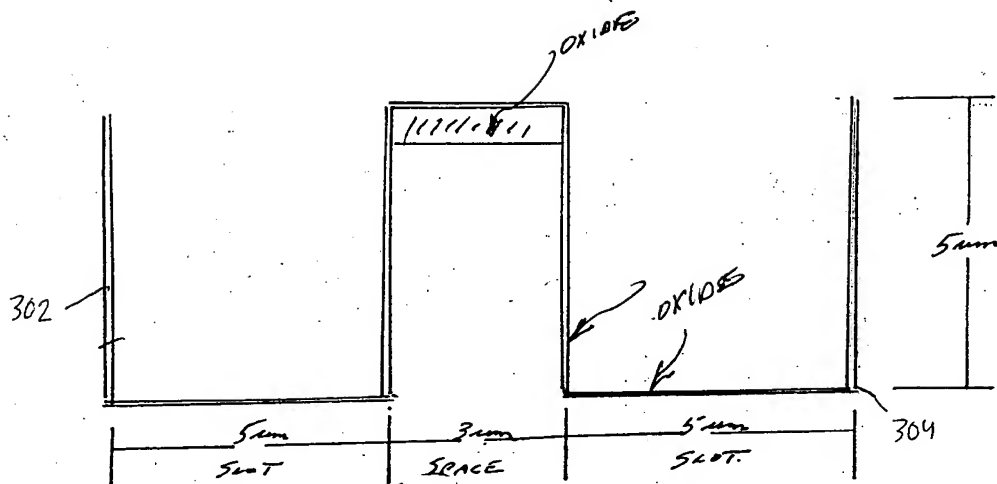


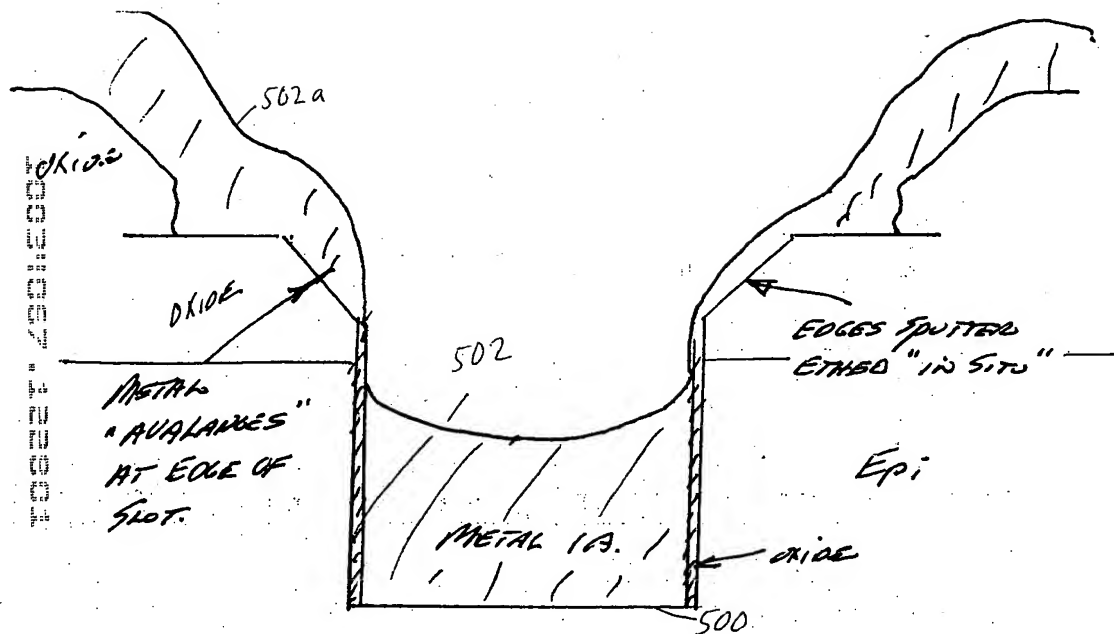
Fig. 4

40021007 10004



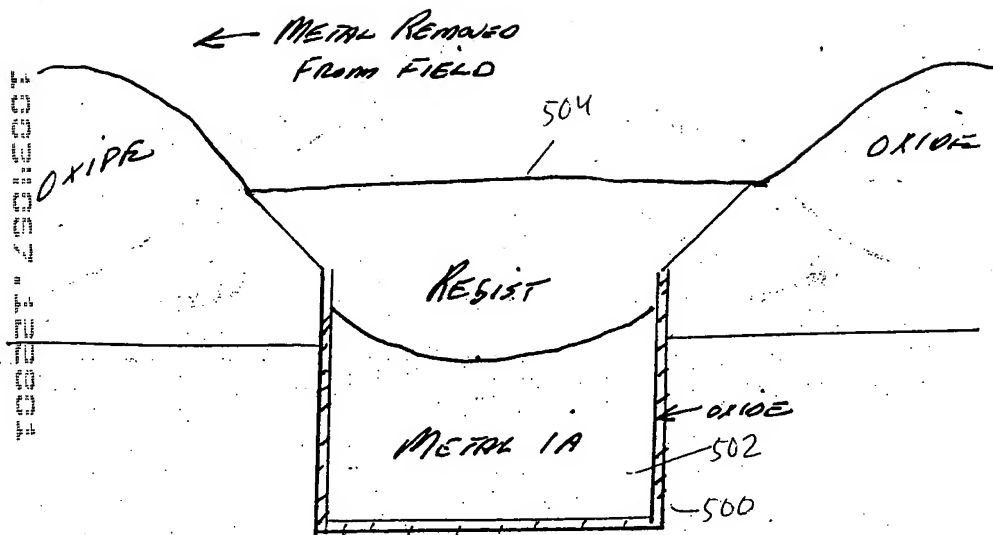
DOUBLE SLOT FOR
DOUBLE WIDTH OF METAL.
3mm SPACE BETWEEN SLOTS

Fig. 4a



PRIOR TO METAL 1A BEING
 SPUTTERED, THE EDGES OF THE OXIDES
 ARE SPUTTER ETCHED "IN SITU" &
 1A DEPOSITED

Fig. 5



RESIST PATTERN ETCHED.
 LEAVING RESIST IN FLATS.
 FIELD METAL ETCHED OFF.

Fig. 7

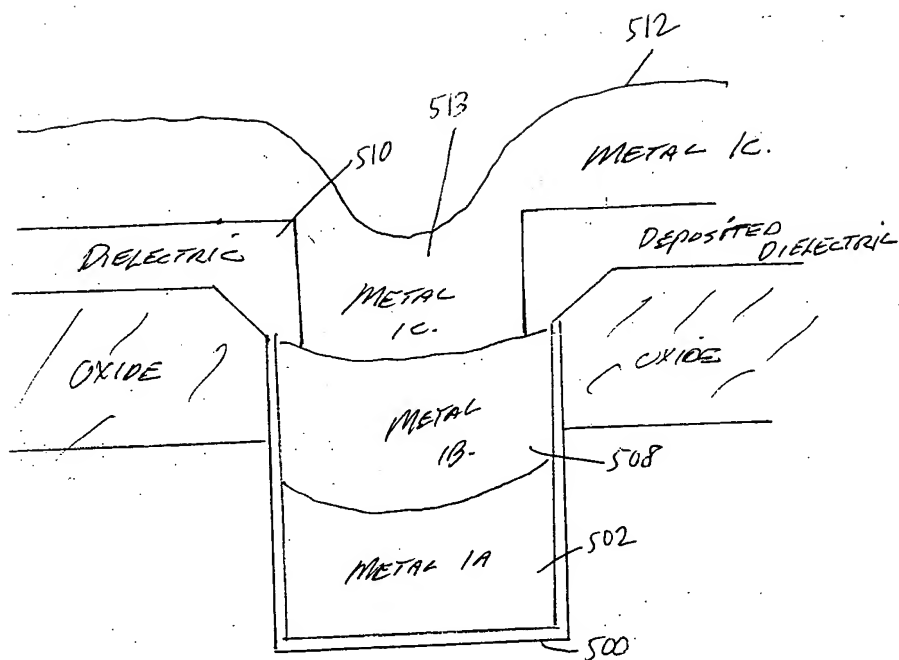


Fig. 9

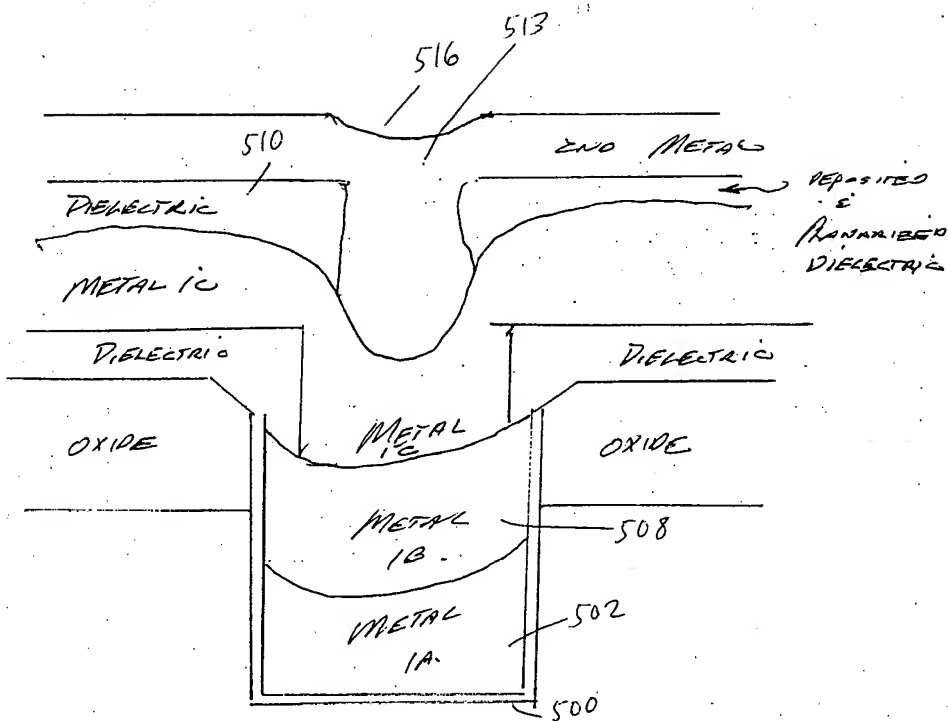
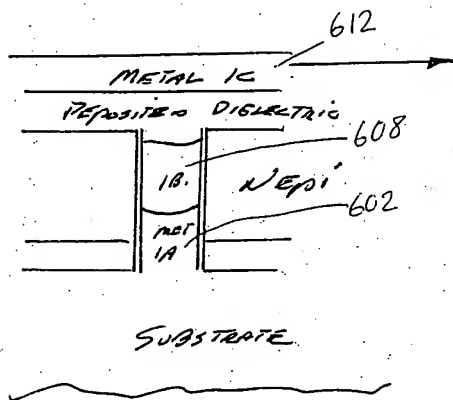


Fig. 10



METAL IC
 CONNECTS AN ISOLATED
 ISLAND TO ADJACENT
 ISOLATED EPI ISLANDS
 AND CROSSES OVER THE
 ISOLATION GROUND
 STRAP BY NOT OPENING
 A VIA IN THIS PORTION
 TO ALLOW IC TO BE
 ISOLATED FROM GROUND.

Fig. 12